#### TTIC 31250 An Introduction to the Theory of Machine Learning

#### Uniform convergence, tail inequalities, VC-dimension I

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# Today: back to distributional setting

- We are given sample S =  $\{(x_i, y_i)\}$ .
  - Assume x's come from some fixed probability distribution D over instance space.
  - View labels y as being produced by some target function. [Or can think of distrib over pairs  $(x_i, y_i)$ .]
- Alg does optimization over S to produce some hypothesis h. Want h to do well on new examples also from D.
- How big does 5 have to be to get this kind of guarantee?

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# Basic sample complexity bound recap

- If  $|S| \ge \frac{1}{\epsilon} \left[ \ln|H| + \ln \frac{1}{\delta} \right]$ , then with probability  $\ge 1 \delta$ , all  $h \in H$  with  $\operatorname{err}_{\mathsf{D}}(\mathsf{h}) \ge \varepsilon$  have  $\operatorname{err}_{\mathsf{S}}(\mathsf{h}) > 0$ .
- Argument: fix bad h. Prob of consistency at most  $(1-\epsilon)^{|S|}$ . Set to  $\delta/|H|$  and use union bound.
- So, if the target concept is in H, and we have an algorithm that can find consistent functions, then we only need this many examples to achieve the PAC guarantee.

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# Uniform Convergence

- Our basic result only bounds the chance that a bad hypothesis looks perfect on the data. What if there is no perfect  $h \in H$ ?
- Without making any assumptions about the target function, can we say that whp all  $h \in H$  satisfy  $|err_{D}(h) err_{S}(h)| \le \epsilon$ ?
  - Called "uniform convergence".
  - Motivates optimizing over S, even if we can't find a perfect function.
- To prove bounds like this, need some good tail inequalities.

#### Today: two issues

- If  $|S| \ge \frac{1}{\epsilon} \left[ \ln|H| + \ln \frac{1}{\delta} \right]$ , then with probability  $\ge 1 \delta$ , all  $h \in H$  with  $\operatorname{err}_{D}(h) \ge \epsilon$  have  $\operatorname{err}_{S}(h) > 0$ .
- Look at more general notions of "uniform convergence".
- Replace In(|H|) with better measures of complexity.

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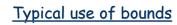
# Tail inequalities

Tail inequality: bound probability mass in tail of distribution.

- Consider a hypothesis h with true error p.
- If we see m examples, then the expected fraction of mistakes is p, and the standard deviation  $\sigma$  is  $(p(1-p)/m)^{1/2}$ .
- A convenient rule for iid Bernoulli trials, in our notation, is:  $Pr[|err_D(h) err_S(h)| > 1.96\sigma] < 0.05.$ 
  - If we want 95% confidence that true and observed errors differ by only  $\epsilon$ , only need (1.96)<sup>2</sup>p(1-p)/ $\epsilon^2 < 1/\epsilon^2$  examples. [worst case is when p=1/2]
- Chernoff and Hoeffding bounds extend to case where we want to show something is really unlikely, so can rule out lots of hypotheses.

Chernoff and Hoeffding bounds	
Consider m flips of a coin of bias p. Let $N_{head}$ be the observed # heads. Let $\varepsilon, \alpha \in [0,1]$ .	s
Hoeffding bounds:	
• $\Pr[N_{heads}/m > p + \varepsilon] \le e^{-2m\varepsilon^2}$ , and	
• $\Pr[N_{heads}/m > p + \varepsilon] \le e^{-2m\varepsilon^2}$ , and • $\Pr[N_{heads}/m .$	
Chernoff bounds:	
• $\Pr[N_{heads} / m > p(1+\alpha)] \le e^{-mp\alpha^2/3}$ , and	
• $\Pr[N_{heads} / m < p(1-\alpha)] \le e^{-mp\alpha^2/2}$ .	
E.g,	
• $\Pr[N_{heads} > 2(expectation)] \le e^{-(expectation)/3}$ .	
<ul> <li>Pr[N<sub>heads</sub> &lt; (expectation)/2] ≤ e<sup>-(expectation)/8</sup></li> </ul>	

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Thm: If  $|S| \ge \frac{1}{2\epsilon^2} \left[ \ln(2|H|) + \ln\left(\frac{1}{\delta}\right) \right]$ , then with prob  $\ge 1 - \delta$ , all  $h \in H$  have  $|err_D(h) - err_S(h)| < \epsilon$ .

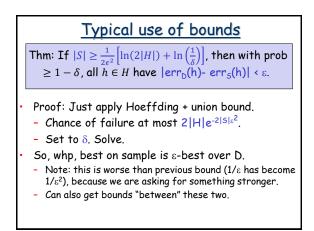
#### • Proof: Just apply Hoeffding + union bound.

- Chance of failure at most  $2|H|e^{-2|S|\epsilon^2}$ .
- Set to  $\delta$ . Solve.

#### Hoeffding bounds:

- $\Pr[N_{heads}/m > p + \varepsilon] \le e^{-2m\varepsilon^2}$
- $\Pr[N_{heads} / m$

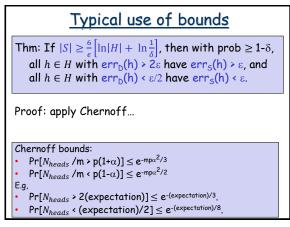




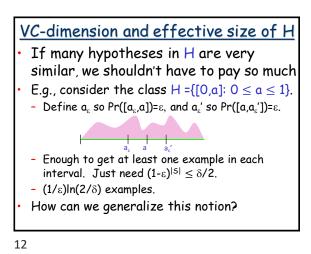
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• For convenience, let's go back to the question: how big does S have to be so that whp,  $err_{S}(h) = 0 \Rightarrow err_{D}(h) \le \varepsilon$ .







# Effective number of hypotheses

Define: H[S] = set of all different ways to label points in S using concepts in H.

Define H[m] = maximum |H[S]| over datasets S of m points.

What is H[m] for "initial intervals"?

# Effective number of hypotheses

Define: H[S] = set of all different ways to label points in S using concepts in H.

Define H[m] = maximum |H[S]| over datasets S of m points.

What is H[m] for linear separators in R<sup>2</sup>?

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# Effective number of hypotheses

Define: H[S] = set of all different ways to label points in S using concepts in H.

Define H[m] = maximum |H[S]| over datasets S of m points.

Thm: For any class H, distribution D, if

 $|S| = m > \frac{2}{\epsilon} \left[ \log_2(2H[2m]) + \log_2\left(\frac{1}{\delta}\right) \right],$ 

then with prob. 1- $\delta$ , all  $h \in H$  with error >  $\varepsilon$  are inconsistent with data. [Will prove next class]

I.e., can roughly replace "|H|" with "H[2m]".

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# Shattering

- Defn: A set of points S is shattered by H if there are concepts in H that label S in all of the 2<sup>|S|</sup> possible ways.
  - In other words, all possible ways of classifying points in S are achievable using concepts in H.
- E.g., any 3 non-collinear points in R<sup>2</sup> can be shattered by linear threshold functions, but no set of 4 points can be.

## Effective number of hypotheses Define: H[S] = set of all different ways to label

points in S using concepts in H.

Define H[m] = maximum |H[S]| over datasets S of m points.

- H[m] is sometimes hard to calculate exactly, but can get a good bound using "VC-dimension".
- VC-dimension is roughly the point at which H stops looking like it contains all functions.

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# VC-dimension

- The VC-dimension of a hypothesis class H is the size of the largest set of points that can be shattered by H. So, if the VC-dimension is d, that means there exists a set of d points that can be shattered, but
- no set of d+1 points can be shartered.
- E.g., VC-dim(linear threshold fns in 2-D) = 3.
- Will later show VC-dim(LTFs in R<sup>n</sup>) = n+1.
- What is the VC-dim of intervals on the real line?
  How about C = {all 0/1 functions on {0,1}<sup>n</sup>}?

#### Upper and lower bound theorems

- Theorem 1: For any class *H*, distribution *D*, if  $m = |S| > \frac{2}{\epsilon} \left[ \log_2(2H[2m]) + \log_2 \frac{1}{\delta} \right]$ , then with prob. 1- $\delta$ , all  $h \in H$  with error >  $\epsilon$  are inconsistent with data.
- Theorem 2 (Sauer's lemma):  $H[m] \leq \sum_{i=0}^{VCdim(H)} {m \choose i} = O(m^{VCdim(H)}).$
- Corollary 3: can replace bound in Thm 1 with  $o\left(\frac{1}{\epsilon}\left[VCdim(H)\log\left(\frac{1}{\epsilon}\right) + \log\left(\frac{1}{\delta}\right)\right]\right)$
- Theorem 4: For any alg A, class H, exists distrib D and target in H such that if  $|S| < \frac{VCdim(H)-1}{8\epsilon}$  then  $E[err_D(A)] \ge \epsilon$ .

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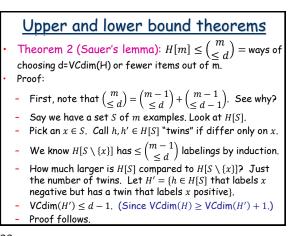
# Upper and lower bound theorems

- Theorem 2 (Sauer's lemma): H[m] ≤ (<sup>m</sup><sub>≤ d</sub>) = ways of choosing d=VCdim(H) or fewer items out of m.
   Proof:
- First, note that  $\binom{m}{\leq d} = \binom{m-1}{\leq d} + \binom{m-1}{\leq d-1}$ . See why?

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# Upper and lower bound theorems Theorem 4: For any alg A, class H, exists distrib D, f ∈ H s.t. if |S| < VCdim(H)-1/8ε then E[err<sub>D</sub>(A)] ≥ ε. Proof: Consider d = VC-dim(H) shattered points. Define distrib D with prob 1 - 4ε on one point and prob 4ε/d-1 on the rest. Pick a random labeling of the d points as the target. E[err<sub>D</sub>(A)] = Pr[mistake on test point] ≥ 1/2 Pr[test point not in S] ≥ 1/2 (4ε) (1 - 4ε/d-1)^{|S|} ≥ (2ε) (1 - 1/2) = ε.

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